

TEMIC

Siliconix

SUP/SUB60P06-20

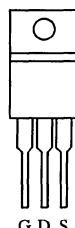
P-Channel Enhancement-Mode Transistor

175°C Maximum Junction Temperature

Product Summary

$V_{(BR)DSS}$ (V)	$r_{DS(on)}$ (Ω)	I_D (A)
-60	0.020	-60 ^a

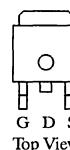
TO-220AB



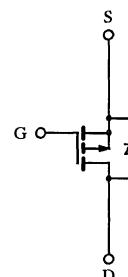
Top View

SUP60P06-20

TO-263



SUP60P06-20



P-Channel MOSFET

Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ($T_J = 175^\circ\text{C}$)	I_D	-60^{a}	A
$T_C = 125^\circ\text{C}$		-55	
Pulsed Drain Current	I_{DM}	-240	
Avalanche Current	I_{AR}	-60	
Repetitive Avalanche Energy ^b	E_{AR}	180	mJ
Power Dissipation	P_D	150	W
$T_A = 125^\circ\text{C}$ (TO-263) ^c		3.7	
Operating Junction and Storage Temperature Range	T_J, T_{Stg}	-55 to 175	°C

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N-P-Channel
MOSFETS

Thermal Resistance Ratings

Parameter	Symbol	Limit	Unit
Junction-to-Ambient	R_{thJA}	40	°C/W
	R_{thJA}	80	
Junction-to-Case	R_{thJC}	1.0	

Notes:

a. Package limited.

b. Duty cycle $\leq 1\%$.

c. When mounted on 1" square PCB (FR-4 material).

Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	-2.0		-4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -48 \text{ V}, V_{GS} = 0 \text{ V}$			-25	
		$V_{DS} = -48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			-250	μA
		$V_{DS} = -48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			-500	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = -5 \text{ V}, V_{GS} = -10 \text{ V}$	-120			A
Drain-Source On-State Resistance ^b	$r_{DS(on)}$	$V_{GS} = -10 \text{ V}, I_D = -30 \text{ A}$			0.020	
		$V_{GS} = -10 \text{ V}, I_D = -30 \text{ A}, T_J = 125^\circ\text{C}$			0.030	Ω
		$V_{GS} = -10 \text{ V}, I_D = -30 \text{ A}, T_J = 175^\circ\text{C}$			0.040	
Forward Transconductance ^b	g_f	$V_{DS} = -15 \text{ V}, I_D = -30 \text{ A}$				S
Dynamic^a						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = -25 \text{ V}, f = 1 \text{ MHz}$		TBD		
Output Capacitance	C_{oss}			TBD		pF
Reversen Transfer Capacitance	C_{rss}			TBD		
Total Gate Charge ^c	Q_g	$V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -60 \text{ A}$		TBD	150	
Gate-Source Charge ^c	Q_{gs}			TBD		nC
Gate-Drain Charge ^c	Q_{gd}			TBD		
Turn-On Delay Time ^c	$t_{d(on)}$	$V_{DD} = -30 \text{ V}, R_L = 0.47 \Omega$ $I_D = -60 \text{ A}, V_{GEN} = -10 \text{ V}, R_G = 2.5 \Omega$		TBD	40	
Rise Time ^c	t_r			TBD	200	
Turn-Off Delay Time ^c	$t_{d(off)}$			TBD	120	ns
Fali Time ^c	t_f			TBD	60	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)^a						
Continuous Current	I_s				-60	A
Pulsed Current	I_{SM}				-240	
Forward Voltage ^b	V_{SD}	$I_F = -60 \text{ A}, V_{GS} = 0 \text{ V}$		TBD	TBD	V
Reverse Recovery Time	t_{rr}	$I_F = -60 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$		TBD	TBD	ns
Peak Reverse Recovery Current	$I_{RM(REC)}$			TBD	TBD	A
Reverse Recovery Charge	Q_{rr}			TBD	TBD	μC

Notes:

- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- c. Independent of operating temperature.